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# 1. Electrical Specifications

**Table 1. DC Electrical Specifications** 

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
3.3 V Operating Voltage	VDD core	3.3 ± 5%	3.135	3.3	3.465	V
3.3 V Input High Voltage	V <sub>IH</sub>	Control input pins	2.0	_	V <sub>DD</sub> + 0.3	V
3.3 V Input Low Voltage	V <sub>IL</sub>	Control input pins	V <sub>SS</sub> - 0.3	_	0.8	V
Input High Voltage	V <sub>IHI2C</sub>	SDATA, SCLK	2.2	_	_	V
Input Low Voltage	V <sub>ILI2C</sub>	SDATA, SCLK	_	_	1.0	V
Input High Leakage Current	I <sub>IH</sub>	Except internal pull-down resistors, 0 < V <sub>IN</sub> < V <sub>DD</sub>	_	_	5	μА
Input Low Leakage Current	I <sub>IL</sub>	Except internal pull-up resistors, 0 < V <sub>IN</sub> < V <sub>DD</sub>	<b>-</b> 5	_	_	μА
3.3 V Output High Voltage (Single-Ended Outputs)	V <sub>OH</sub>	I <sub>OH</sub> = -1 mA	2.4	_	_	V
3.3 V Output Low Voltage (Single-Ended Outputs)	V <sub>OL</sub>	I <sub>OL</sub> = 1 mA	_	_	0.4	V
High-impedance Output Current	I <sub>OZ</sub>		-10	_	10	μΑ
Input Pin Capacitance	C <sub>IN</sub>		1.5	_	5	pF
Output Pin Capacitance	C <sub>OUT</sub>		_	_	6	pF
Pin Inductance	L <sub>IN</sub>		_	_	7	nΗ
Dynamic Supply Current	I <sub>DD_3.3V</sub>	All outputs enabled. Differential clock with 5" traces and 2 pF load at 100 MHz.	_	_	20	mA



**Table 2. AC Electrical Specifications** 

f <sub>in</sub>		•		•	•
fin					
111		100	_	210	MHz
T <sub>R</sub> / T <sub>F</sub>	Single ended measurement: $V_{OL} = 0.175$ to $V_{OH} = 0.525$ V (Averaged)	0.6	_	4	V/ns
V <sub>IH</sub>		150	_	_	mV
$V_{IL}$		_	_	-150	mV
V <sub>OX</sub>	Single-ended measurement	250	_	550	mV
$\Delta V_{OX}$	Single-ended measurement	_	_	140	mV
V <sub>RB</sub>		-100	_	100	mV
T <sub>STABLE</sub>		500	_	_	ps
V <sub>MAX</sub>			_	1.15	V
V <sub>MIN</sub>		-0.3	_	_	٧
T <sub>DC</sub>	Measured at crossing point V <sub>OX</sub>	45	_	55	%
T <sub>RFM</sub>	Determined as a fraction of $2 \times (T_R - T_F)/(T_R + T_F)$	_	_	20	%
$T_DC$	Measured at 0 V differential	45	_	55	%
T <sub>SKEW</sub>	Measured at 0 V differential	_	_	50	ps
Pk-Pk		0	_	10	ps
RMS <sub>GEN2</sub>	10 kHz < F < 1.5 MHz	0	_	0.5	ps
-	1.5 MHz< F < Nyquist Rate	0	_	0.5	ps
chase Jitter  RMS <sub>GEN3</sub> Includes PLL BW 2–4 MHz (CDR = 10 MHz)		0	_	0.10	ps
RMS <sub>GEN4</sub>	PCIe Gen 4	_	_	0.10	ps
T <sub>CCJ</sub>	Measured at 0 V differential	_	_	50	ps
_	Measured at 0 V differential	_	_	100	ppm
	VIH VIL VOX  AVOX VRB TSTABLE VMAX  VMIN  TDC  TRFM  TDC  TSKEW Pk-Pk  RMSGEN2  RMSGEN4	$V_{OL} = 0.175 \text{ to } V_{OH} = 0.525 \text{ V} \\ \text{(Averaged)}$ $V_{IH}$ $V_{IL}$ $V_{OX}$ $Single-ended measurement$ $V_{RB}$ $T_{STABLE}$ $V_{MAX}$ $V_{MIN}$ $T_{DC}$ $Measured at crossing point V_{OX} T_{RFM} Determined as a fraction of 2 x (T_R - T_F)/(T_R + T_F) T_{DC} Measured at 0 V differential T_{SKEW} Measured at 0 V differential Pk-Pk RMS_{GEN2} 10 \text{ kHz} < F < 1.5 \text{ MHz} 1.5 \text{ MHz} < F < Nyquist Rate} RMS_{GEN3} Includes PLL BW 2-4 \text{ MHz} \\ (CDR = 10 \text{ MHz}) RMS_{GEN4} PCIe Gen 4 T_{CCJ} Measured at 0 V differential$	V <sub>OL</sub> = 0.175 to V <sub>OH</sub> = 0.525 V (Averaged)           V <sub>IH</sub> 150           V <sub>IL</sub> —           V <sub>OX</sub> Single-ended measurement         250           ΔV <sub>OX</sub> Single-ended measurement         —           V <sub>RB</sub> —100         —           T <sub>STABLE</sub> 500         —           V <sub>MAX</sub> —         —           T <sub>DC</sub> Measured at crossing point V <sub>OX</sub> 45           T <sub>RFM</sub> Determined as a fraction of 2 x (T <sub>R</sub> − T <sub>F</sub> )/(T <sub>R</sub> + T <sub>F</sub> )         —           T <sub>DC</sub> Measured at 0 V differential         —           T <sub>SKEW</sub> Measured at 0 V differential         —           Pk-Pk         0         0           RMS <sub>GEN2</sub> 10 kHz < F < 1.5 MHz	V <sub>OL</sub> = 0.175 to V <sub>OH</sub> = 0.525 V (Averaged)         150         —           V <sub>IL</sub> 150         —           V <sub>OX</sub> Single-ended measurement         250         —           ΔV <sub>OX</sub> Single-ended measurement         —         —           V <sub>RB</sub> −100         —           T <sub>STABLE</sub> 500         —           V <sub>MAX</sub> —         —           V <sub>MIN</sub> −0.3         —           T <sub>DC</sub> Measured at crossing point V <sub>OX</sub> 45         —           T <sub>RFM</sub> Determined as a fraction of 2 x (T <sub>R</sub> − T <sub>F</sub> )/(T <sub>R</sub> + T <sub>F</sub> )         —         —           T <sub>DC</sub> Measured at 0 V differential         45         —           T <sub>SKEW</sub> Measured at 0 V differential         —         —           Pk-Pk         0         —           RMS <sub>GEN2</sub> 10 kHz < F < 1.5 MHz	V <sub>OL</sub> = 0.175 to V <sub>OH</sub> = 0.525 V (Averaged)         V <sub>IH</sub> 150       —       —         V <sub>IL</sub> —       —       —       —         V <sub>OX</sub> Single-ended measurement       250       —       550         ΔV <sub>OX</sub> Single-ended measurement       —       —       140         V <sub>RB</sub> —       —       100       —       100         T <sub>STABLE</sub> 500       —       —       —         V <sub>MAX</sub> —       —       —       —       —         V <sub>MIN</sub> —       —       —       —       —         T <sub>DC</sub> Measured at crossing point V <sub>OX</sub> 45       —       55         T <sub>RFM</sub> Determined as a fraction of 2 x (T <sub>R</sub> – T <sub>F</sub> )/(T <sub>R</sub> + T <sub>F</sub> )       —       —       20         T <sub>SKEW</sub> Measured at 0 V differential       —       —       55         T <sub>SKEW</sub> Measured at 0 V differential       —       —       55         RMS <sub>GEN2</sub> 10 kHz < F < 1.5 MHz

### Notes:

- Gen 4 specifications based on the PCI-Express Base Specification 4.0 rev. 0.5.
   Download the Silicon Labs PCIe Clock Jitter Tool at www.silabs.com/pcie-learningcenter.



**Table 2. AC Electrical Specifications (Continued)** 

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Rising/Falling Slew Rate	T <sub>R</sub> / T <sub>F</sub>	Measured differentially from ±150 mV	2.5	_	8	V/ns
Crossing Point Voltage at 0.7 V Swing	V <sub>OX</sub>		300	_	550	mV
Enable/Disable and Set-Up						
Clock Stabilization from Power-up	T <sub>STABLE</sub>	Measured from the point when both V <sub>DD</sub> and clock input are valid	_	_	5	ms
Stopclock Set-up Time	T <sub>SS</sub>		10.0	_	_	ns

### Notes:

- 1. Gen 4 specifications based on the PCI-Express Base Specification 4.0 rev. 0.5.
- 2. Download the Silicon Labs PCIe Clock Jitter Tool at www.silabs.com/pcie-learningcenter.

**Table 3. Absolute Maximum Conditions** 

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Main Supply Voltage	$V_{DD_3.3V}$	Functional	_	_	4.6	V
Input Voltage	V <sub>IN</sub>	Relative to V <sub>SS</sub>	-0.5	_	4.6	$V_{DC}$
Temperature, Storage	T <sub>S</sub>	Non-functional	-65	_	150	°C
Temperature, Operating Ambient	T <sub>A</sub>	Functional	-40	_	85	°C
Temperature, Junction	TJ	Functional	_	_	150	°C
Dissipation, Junction to Case	Ø <sub>JC</sub>	JEDEC (JESD 51)	_	_	35	°C/W
Dissipation, Junction to Ambient	Ø <sub>JA</sub>	JEDEC (JESD 51)	_	_	37	°C/W
ESD Protection (Human Body Model)	ESD <sub>HBM</sub>	JEDEC (JESD 22-A114)	2000	_	_	V
Flammability Rating	UL-94	UL (Class)		V-0		

**Note:** While using multiple power supplies, the voltage on any input or I/O pin cannot exceed the power pin during power-up. Power supply sequencing is not required.



# 2. Functional Description

## 2.1. OE Pin Definition

The OE pins are active high inputs used to enable and disable the output clocks. To enable the output clock, the OE pin needs to be logic high and the  $I^2C$  output enable bit needs to be logic high. There are two methods to disable the output clocks: the OE is pulled to a logic low, or the  $I^2C$  enable bit is set to a logic low. The OE pins are required to be driven at all times even though they have an internal 100 k $\Omega$  resistor.

### 2.2. OE Assertion

The OE signals are active high inputs used for synchronous stopping and starting the DIFF output clocks respectively while the rest of the clock generator continues to function. The assertion of the OE signal by making it logic high causes stopped respective DIFF outputs to resume normal operation. No short or stretched clock pulses are produced when the clock resumes. The maximum latency from the assertion to active outputs is no more than two to six output clock cycles.

### 2.3. OE Deassertion

When the OE pin is deasserted by making it logic low, the corresponding DIFF output is stopped, and the final output state is driven low.



# 3. Test and Measurement Setup

This diagram shows the test load configuration for differential clock signals.

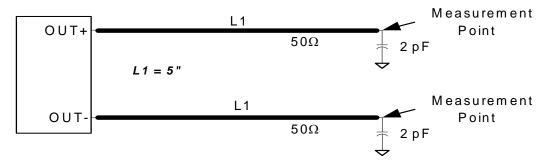
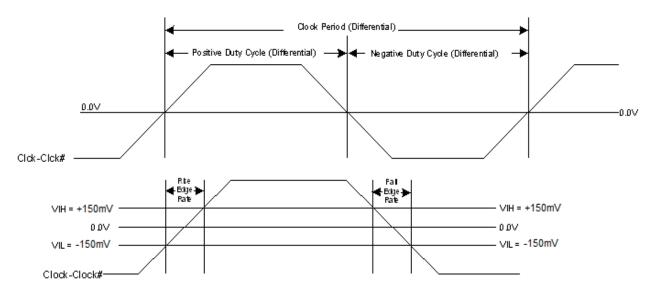


Figure 1. 0.7 V Differential Load Configuration



**Figure 2. Differential Output Signals (for AC Parameters Measurement)** 



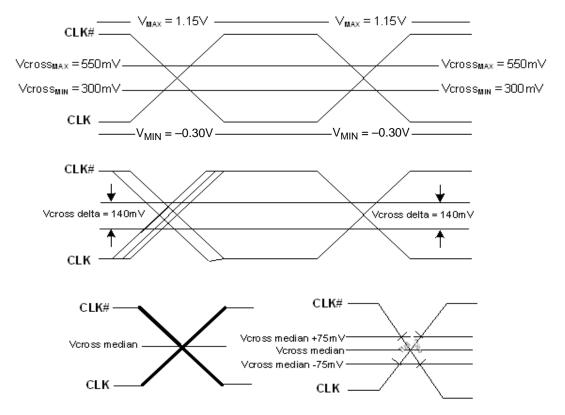


Figure 3. Single-ended Measurement for Differential Output Signals (for AC Parameters Measurement)

## 4. Control Registers

# 4.1. I<sup>2</sup>C Interface

To enhance the flexibility and function of the clock buffer, an I<sup>2</sup>C interface is provided. Through the I<sup>2</sup>C Interface, various device functions are available, such as individual clock output enable. The registers associated with the I<sup>2</sup>C Interface initialize to their default setting at power-up. The use of this interface is optional. Clock device register changes are normally made at system initialization, if any are required. Power management functions can only be programed in program mode and not in normal operation modes.

## 4.2. Data Protocol

The I<sup>2</sup>C protocol accepts byte write, byte read, block write, and block read operations from the controller. For block write/read operation, access the bytes in sequential order from lowest to highest (most significant bit first) with the ability to stop after any complete byte is transferred. For byte write and byte read operations, the system controller can access individually indexed bytes.

The block write and block read protocol is outlined in Table 4 while Table 5 outlines byte write and byte read protocol. The slave receiver address is 11010110 (D6h).

Table 4. Block Read and Block Write Protocol

	Block Write Protocol		Block Read Protocol
Bit	Description	Bit	Description
1	Start	1	Start
8:2	Slave address—7 bits	8:2	Slave address—7 bits
9	Write	9	Write
10	Acknowledge from slave	10	Acknowledge from slave
18:11	Command Code—8 bits	18:11	Command Code—8 bits
19	Acknowledge from slave	19	Acknowledge from slave
27:20	Byte Count—8 bits	20	Repeat start
28	Acknowledge from slave	27:21	Slave address—7 bits
36:29	Data byte 1—8 bits	28	Read = 1
37	Acknowledge from slave	29	Acknowledge from slave
45:38	Data byte 2—8 bits	37:30	Byte Count from slave—8 bits
46	Acknowledge from slave	38	Acknowledge
	Data Byte /Slave Acknowledges	46:39	Data byte 1 from slave—8 bits
	Data Byte N—8 bits	47	Acknowledge
	Acknowledge from slave	55:48	Data byte 2 from slave—8 bits
	Stop	56	Acknowledge
			Data bytes from slave/Acknowledge
			Data Byte N from slave–8 bits
			NOT Acknowledge
			Stop



**Table 5. Byte Read and Byte Write Protocol** 

	Byte Write Protocol		Byte Read Protocol
Bit	Description	Bit	Description
1	Start	1	Start
8:2	Slave address–7 bits	8:2	Slave address–7 bits
9	Write	9	Write
10	Acknowledge from slave	10	Acknowledge from slave
18:11	Command Code-8 bits	18:11	Command Code–8 bits
19	Acknowledge from slave	19	Acknowledge from slave
27:20	Data byte–8 bits	20	Repeated start
28	Acknowledge from slave	27:21	Slave address–7 bits
29	Stop	28	Read
		29	Acknowledge from slave
		37:30	Data from slave–8 bits
		38	NOT Acknowledge
		39	Stop

## Control Register 0. Byte 0

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name								
Туре	R/W							

Reset settings = 00000000

Bit	Name	Function
7:0	Reserved	

# Control Register 1. Byte 1

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name								
Туре	R/W							

Reset settings = 00000000

Bit	Name	Function
7:0	Reserved	



## Control Register 2. Byte 2

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	DIFF0_OE	DIFF1_OE						
Туре	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

Reset settings = 11000000

Bit	Name	Function
7	DIFF0_OE	Output Enable for DIFF0.  0: Output disabled.  1: Output enabled.
6	DIFF1_OE	Output Enable for DIFF1 0: Output disabled. 1: Output enabled.
5:0	Reserved	

# Control Register 3. Byte 3

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	Name Rev Code[3:0]				Vendor ID[3:0]			
Туре	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

Reset settings = 00001000

Bit	Name	Function	
7:4	Rev Code[3:0]	Program Revision Code.	
3:0	Vendor ID[3:0]	Vendor Identification Code.	

## Control Register 4. Byte 4

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name		BC[7:0]						
Type	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

Reset settings = 00000110

Bit	Name	Function
7:0	BC[7:0]	Byte Count Register.



## Control Register 5. Byte 5

Bit	D7	D6	D5	D4	D3	D2	D1	D0
Name	DIFF_Amp_Sel	DIFF_Amp_Cntl[2]	DIFF_Amp_Cntl[1]	DIFF_Amp_Cntl[0]				
Туре	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

## Reset settings = 11011000

Bit	Name	Function		
7	DIFF_Amp_Sel	Amplitude Control for DIFF Differential Outputs.  0: Differential outputs with Default amplitude.  1: Differential outputs amplitude is set by Byte 5[6:4].		
6	DIFF_Amp_Cntl[2]	DIFF Differential Outputs Amplitude Adjustment.		
5	DIFF_Amp_Cntl[1]	000: 300 mV 001: 400 mV 010: 500 mV 011: 600 mV		
4	DIFF_Amp_Cntl[0]	100: 700 mV 101: 800 mV 110: 900 mV 111: 1000 mV		
3:0	Reserved			



# 5. Pin Descriptions: 24-Pin QFN

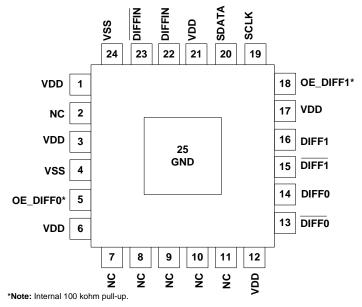


Figure 4. 24-Pin QFN

Table 6. Si53152 24-Pin QFN Descriptions

Pin#	Name	Туре	Description
1	VDD	PWR	3.3 V power supply.
2	NC	NC	No connect.
3	VDD	PWR	3.3 V power supply.
4	VSS	GND	Ground.
5	OE_DIFF0	I,PU	Active high input pin enables DIFF0 (internal 100 k $\Omega$ pull-up). Refer to Table 1 on page 4 for OE specifications.
6	VDD	PWR	3.3 V power supply.
7	NC	NC	No connect.
8	NC	NC	No connect.
9	NC	NC	No connect.
10	NC	NC	No connect.
11	NC	NC	No connect.
12	VDD	PWR	3.3 V power supply.
13	DIFF0	O, DIF	0.7 V, 100 MHz differential clock.
14	DIFF0	O, DIF	0.7 V, 100 MHz differential clock.
15	DIFF1	O, DIF	0.7 V, 100 MHz differential clock.



# Si53152

# Table 6. Si53152 24-Pin QFN Descriptions (Continued)

Pin#	Name	Туре	Description
16	DIFF1	O, DIF	0.7 V, 100 MHz differential clock.
17	VDD	PWR	3.3 V power supply.
18	OE_DIFF1	I,PU	Active high input pin enables DIFF1 (internal 100 k $\Omega$ pull-up). Refer to Table 1 on page 4 for OE specifications.
19	SCLK	I	SMBus compatible SCLOCK.
20	SDATA	I/O	SMBus compatible SDATA.
21	VDD	PWR	3.3 V power supply.
22	DIFFIN	I	0.7 V Differential True Input, typically 100 MHz. Input frequency range 100 to 210 MHz.
23	DIFFIN	0	0.7 V Differential Complement Input, typically 100 MHz. Input frequency range 100 to 210 MHz.
24	VSS	GND	Ground.
25	GND	GND	Ground for bottom pad of the IC.



# 6. Ordering Guide

Part Number	Package Type	Temperature
Lead-free		
Si53152-A01AGM	24-pin QFN	Extended, -40 to 85 °C
Si53152-A01AGMR	24-pin QFN—Tape and Reel	Extended, -40 to 85 °C



# 7. Package Outline

Figure 5 illustrates the package details for the Si53152. Table 7 lists the values for the dimensions shown in the illustration.

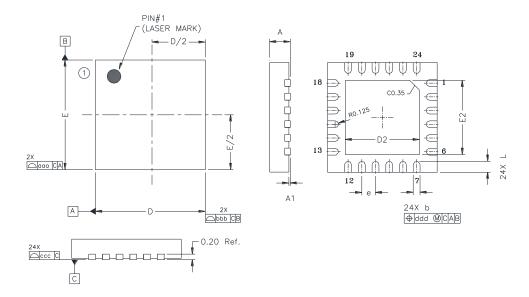


Figure 5. 24-Pin Quad Flat No Lead (QFN) Package

**Table 7. Package Diagram Dimensions** 

Symbol		Millimeters			
	Min	Nom	Max		
А	0.70	0.75	0.80		
A1	0.00	0.025	0.05		
b	0.20	0.25	0.30		
D	4.00 BSC				
D2	2.60	2.70	2.80		
е	0.50 BSC				
Е		4.00 BSC			
E2	2.60	2.70	2.80		
L	0.30	0.40	0.50		
aaa	0.10				
bbb	0.10				
ccc	0.08				
ddd		0.07			

### Notes:

- All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
- 3. This drawing conforms to JEDEC outline MO-220, variation VGGD-8
- **4.** Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components

SHIFTON LARS

# 8. PCB Land Pattern

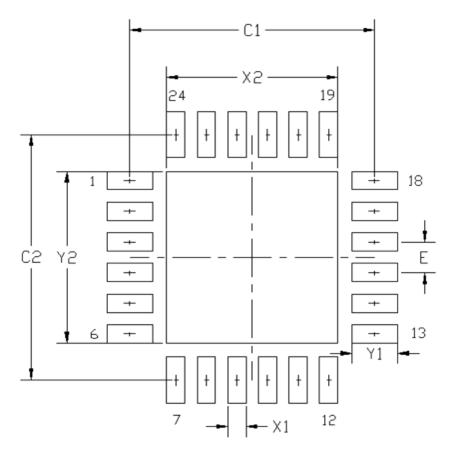


Figure 6. Si53152 24-Pin TDFN Land Pattern

Table 8. Si53152 24-Pin Land Pattern Dimensions

Dimension	mm
C1	4.0
C2	4.0
E	0.50 BSC
X1	0.30
X2	2.70
Y1	0.80



## Table 8. Si53152 24-Pin Land Pattern Dimensions (Continued)

#### Notes:

#### General

- 1. All dimensions shown are in millimeters (mm).
- 2. This Land Pattern Design is based on the IPC-7351 guidelines.
- All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

## Solder Mask Design

**4.** All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60  $\mu$ m minimum, all the way around the pad.

### Stencil Design

- A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 6. The stencil thickness should be 0.125 mm (5 mils).
- 7. The ratio of stencil aperture to land pad size should be 1:1 for all pads.

### **Card Assembly**

- 8. A No-Clean, Type-3 solder paste is recommended.
- The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.



## **DOCUMENT CHANGE LIST**

## **Revision 0.1 to Revision 1.0**

- Updated Features and Description.
- Updated Table 2.
- Updated Table 3.
- Updated Section 4.1.

## **Revision 1.0 to Revision 1.1**

- Updated Features on page 1.
- Updated Description on page 1.
- Updated specs in Table 2, "AC Electrical Specifications," on page 5.

## **Revision 1.1 to Revision 1.2**

 Added condition for Clock Stabilization from Powerup, T<sub>STABLE</sub>, in Table 2.











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